Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/922,442	LIANG ET AL.
Examiner	Art Unit
Matthew W. Genack	2617

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	ence search tout	7/10/2006	M.G.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Consulted with Primary Examiner Ovidio Escalante	6/22/2005	M.G.
Conducted class/subclass and keyword search with EAST	6/22/2005	M.G.
455/63.1, 455/63.4, 455/428, 455/562.1 (Limited text searchsee search history printout)	6/22/2005	M.G.
Consulted with Primary Examiner Dao Phan	1/31/2006	M.G.
Consulted with Primary Examiner Gregory Issing	1/31/2006	M.G.
342/368, 342/372, 342/373 (Limited text search—see search history printout)	1/31/2006	M.G.
Updated text search (See search history printout)	1/31/2006	M.G.
Updated text search (See search history printout)	7/10/2006	M.G.

Search Notes (continued)

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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Conducted NPL search with IEEE Xplore (See printout)	7/10/2006	M.G.